

Description

The XPX150N3AS uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 6V. This device is suitable for use as a Battery protection or in other Switching application.



General Features

$V_{DS} = 150V$ $I_D = 4A$

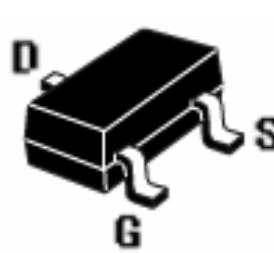
$R_{DS(ON)} < 300m\Omega$ @ $V_{GS} = 10V$

Application

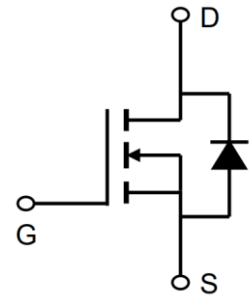
Battery protection

Load switch

Uninterruptible power supply



SOT-23



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
XPX150N3AS	SOT-23-3L	MAB5	3000

Absolute Maximum Ratings ($T_C = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	150	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_A = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	4	A
$I_D @ T_A = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	1.5	A
I_{DM}	Pulsed Drain Current ²	9	A
$P_D @ T_A = 25^\circ C$	Total Power Dissipation ³	2	W
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ C$
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ C$
$R_{\theta JA}$	Thermal Resistance Junction-ambient ¹	125	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	80	$^\circ C/W$

150V N-Channel Enhancement Mode MOSFET
150V N-Channel Enhancement Mode MOSFET
Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Condition	Min	Typ	Max	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V I _D =250μA	150	165	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =150V, V _{GS} =0V	-	-	1	μA
I _{GSS}	Gate-Body Leakage Current	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	1.0	1.8	3.0	V
R _{DS(on)}	Drain-Source On-State Resistance	V _{GS} =10V, I _D =1.5A	-	220	280	mΩ
		V _{GS} =4.5V, I _D =1.5A	-	230	300	mΩ
G _{fs}	Forward Transconductance	V _{DS} =15V, I _D =1.5A	-	3	-	S
C _{iss}	Input Capacitance	V _{DS} =25V, V _{GS} =0V, F=1.0MHz	-	235	-	PF
C _{oss}	Output Capacitance		-	36	-	PF
C _{rss}	Reverse Transfer Capacitance		-	20	-	PF
t _{d(on)}	Turn-on Delay Time	V _{DD} =75V, I _D =1A, R _L =75Ω V _{GS} =10V, R _G =6Ω	-	8	-	nS
t _r	Turn-on Rise Time		-	10	-	nS
t _{d(off)}	Turn-Off Delay Time		-	20	-	nS
t _f	Turn-Off Fall Time		-	15	-	nS
Q _g	Total Gate Charge	V _{DS} =75V, I _D =1.5A, V _{GS} =10V	-	8	-	nC
Q _{gs}	Gate-Source Charge		-	1.4	-	nC
Q _{gd}	Gate-Drain Charge		-	2.1	-	nC
V _{SD}	Diode Forward Voltage ^(Note 3)	V _{GS} =0V, I _S =2A	-	-	1.2	V
I _S	Diode Forward Current ^(Note 2)		-	-	2	A

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 20Z copper.
- 2.The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3.The power dissipation is limited by 150°C junction temperature
- 4 .The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

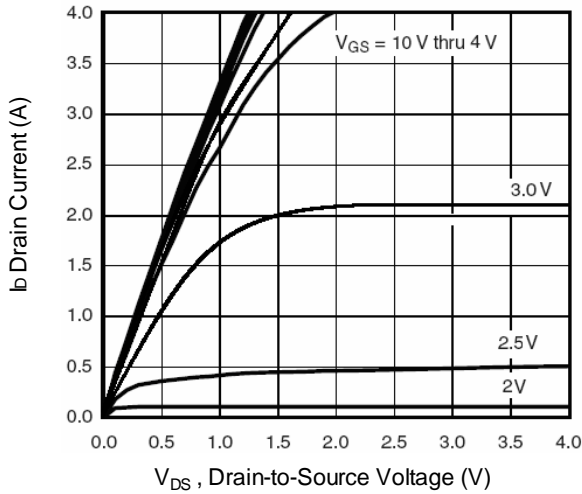


Fig.1 Typical Output Characteristics

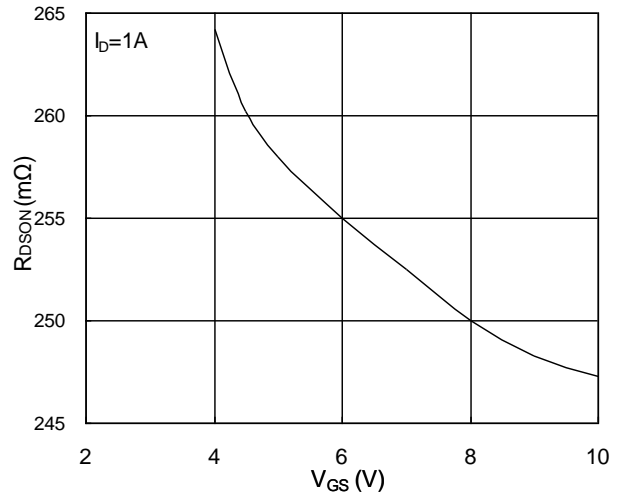


Fig.2 On-Resistance vs. Gate-Source

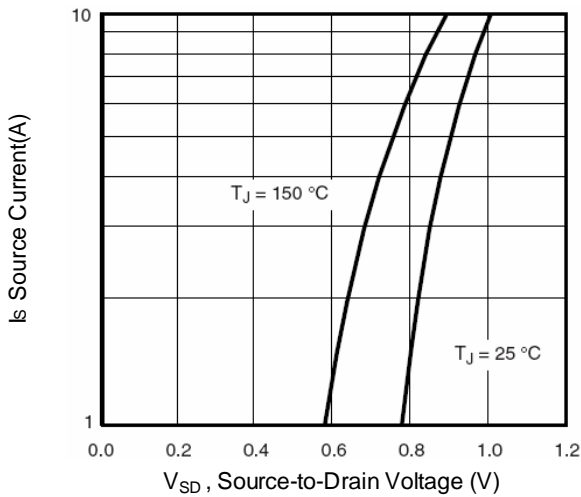


Fig.3 Forward Characteristics of Reverse

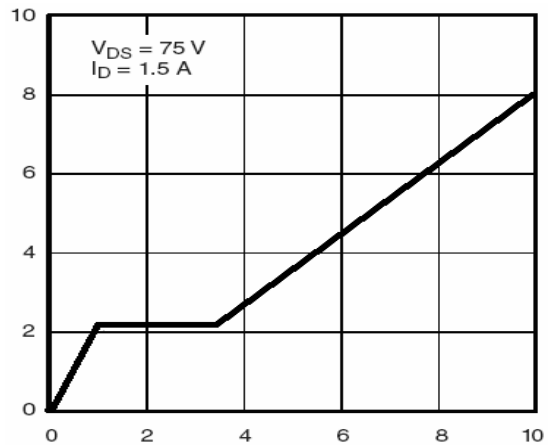


Fig.4 Gate-Charge Characteristics

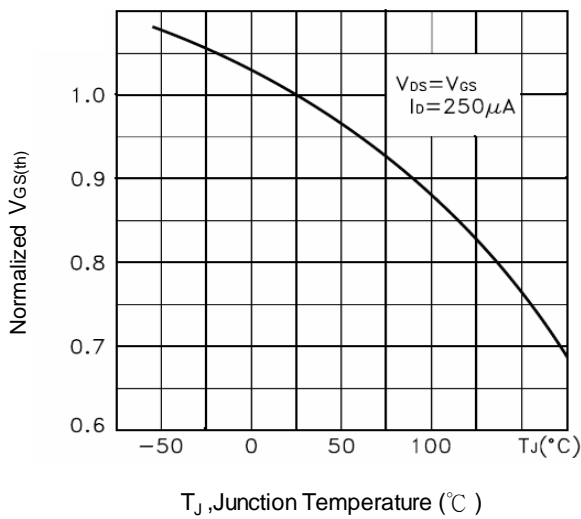


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

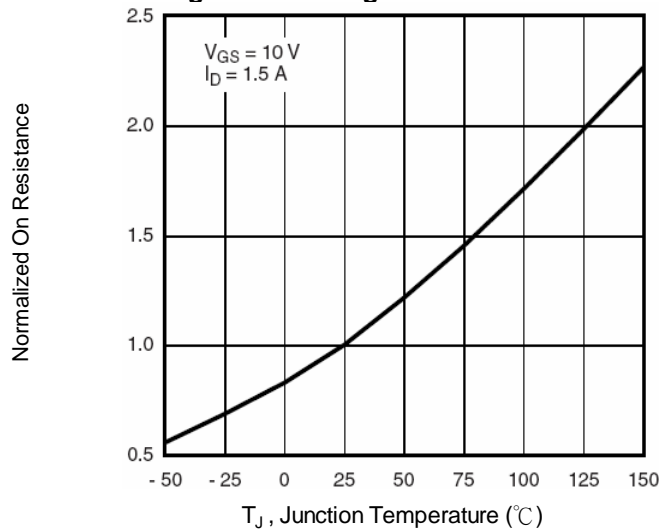


Fig.6 Normalized $R_{DS(on)}$ vs. T_J

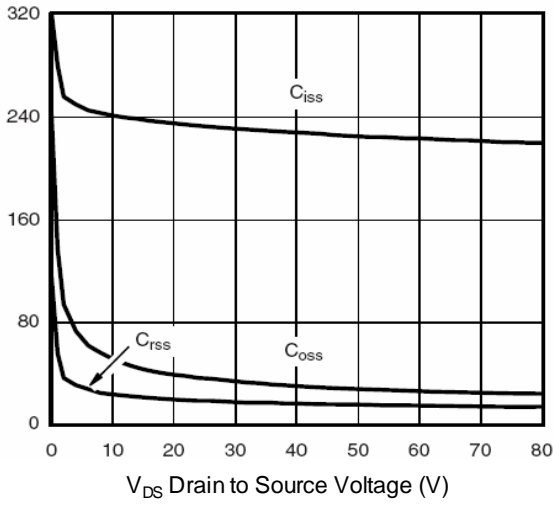


Fig.7 Capacitance

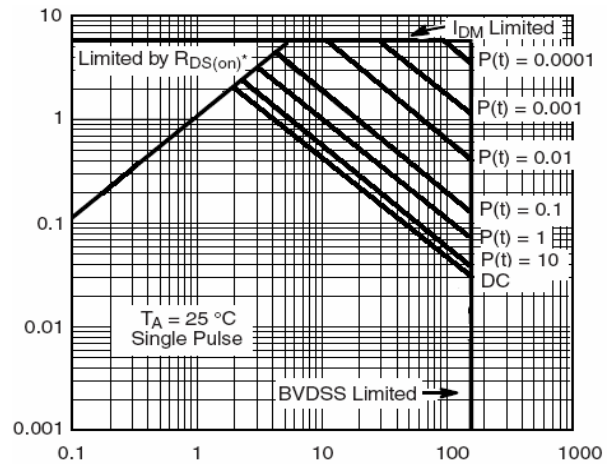


Fig.8 Safe Operating Area

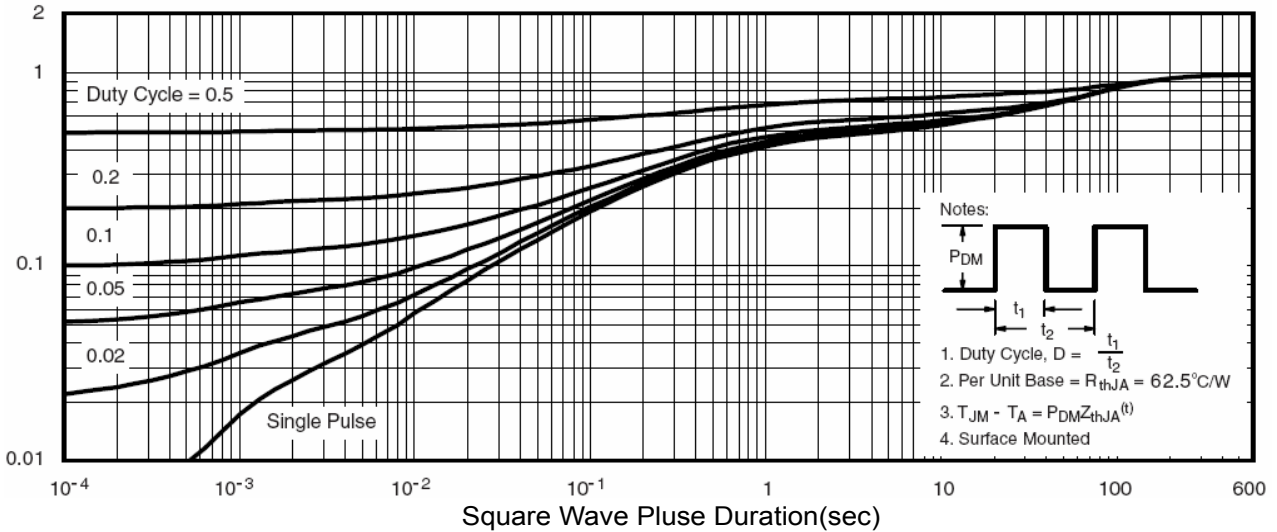


Fig.9 Normalized Maximum Transient Thermal Impedance

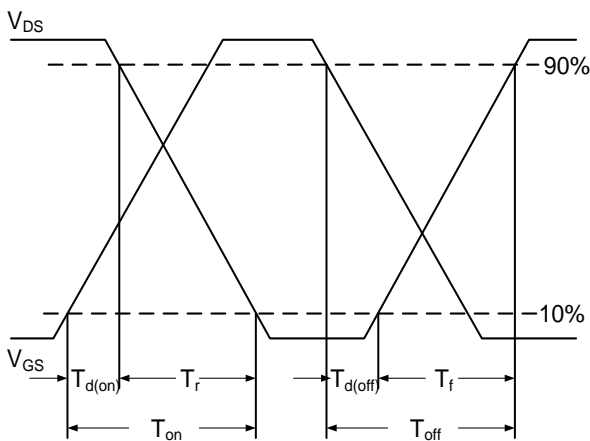


Fig.10 Switching Time Waveform

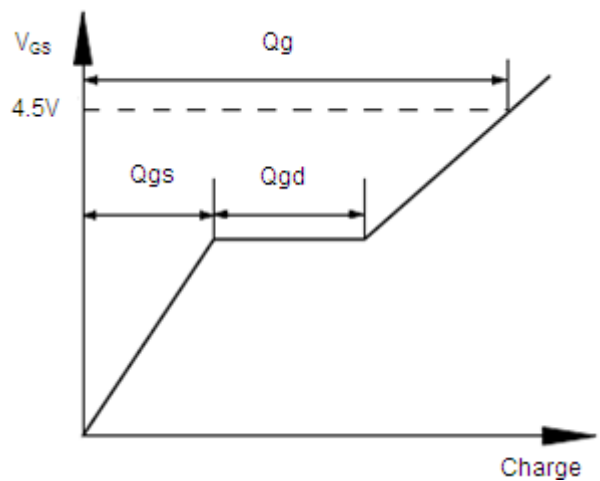
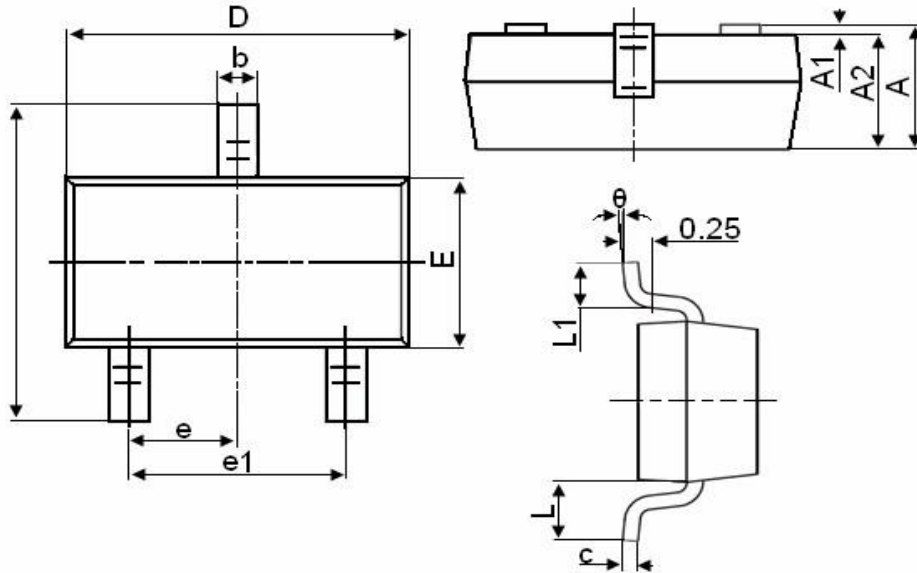


Fig.11 Gate Charge Waveform



Symbol	Dimensions in Millimeters	
	MIN.	MAX.
A	0.900	1.150
A1	0.000	0.100
A2	0.900	1.050
b	0.300	0.500
c	0.080	0.150
D	2.800	3.000
E	1.200	1.400
E1	2.250	2.550
e	0.950TYP	
e1	1.800	2.000
L	0.550REF	
L1	0.300	0.500
θ	0°	8°

Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245°C ±5°C	5sec ±1sec
Pb-Free device	260°C +0/-5°C	5sec ±1sec



This integrated circuit can be damaged by ESD. UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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